



IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 10/626,543
Applicant : Hirofumi HIRAYAMA
Filed : July 25, 2003
TC/A.U. : 3742
Examiner : Mark H. Paschall

Docket No. : 1137-836
Customer No. : 06449
Confirmation No. : 1162

SUPPLEMENTAL
INFORMATION DISCLOSURE STATEMENT

Director of the United States Patent
and Trademark Office
P.O. Box 1450
Alexandria, Virginia 22313-1450

Dear Sir:

Under the provisions of 37 C.F.R. §§ 1.56, 1.97 and 1.98,
Applicant submits herewith information that the Office may wish
to consider in examination of the subject application. Materials
submitted for consideration are listed on the attached form PTO-
1449.

I hereby certify that each item of information contained in
this information disclosure statement was first cited in a
communication from a foreign patent office in a counterpart
foreign application not more than three months prior to the
filing of this statement.

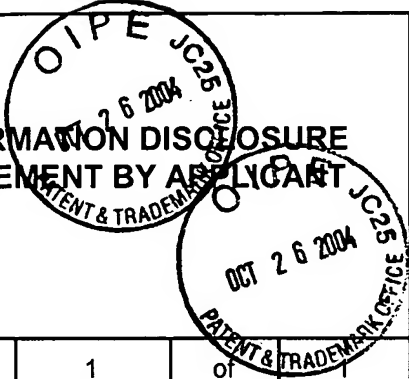
Respectfully submitted,

ROTHWELL, FIGG, ERNST & MANBECK, p.c.

By Vincent M De Luca

Vincent M. DeLuca
Attorney for Applicants
Registration No. 32,408

1425 K Street, N.W.
Suite 800
Washington, D.C. 20005
Telephone: (202)783-6040

 INFORMATION DISCLOSURE STATEMENT BY APPLICANT			<i>Complete if Known</i>		
			Application Number	10/626,543	
			Filing Date	July 25, 2003	
			First Named Inventor	Hirofumi HIROYAMA	
			Group Art Unit	3742	
			Examiner Name	Mark H. Paschall	
Sheet	1	of	Attorney Docket Number	1137-836	

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code ² (if known)		

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T ⁶
		Office ³ Code	Number ⁴	Kind ⁵ (if known)			
		JP	2-253316	A	OMRON TATEISI ELECTRON CO.	10-12-1990	Ab
		JP	5-25502	U		04-02-1993	Ctm
		JP	11-345002	A	HITACHI LTD.; HITACHI ENG. CO. LTD.	12-14-1999	Ab

Examiner Signature		Date Considered	
-----------------------	--	--------------------	--

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code.

⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind